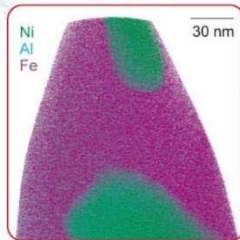


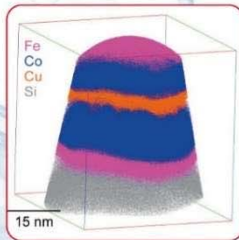
Atom Probe Tomography Seminar

April 25th 2017, 12 noon to 1pm

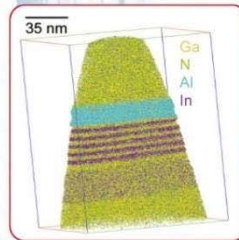
ERB154, Materials Characterization Facility, 1617 Research Parkway



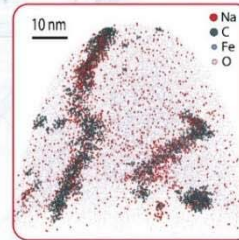
Advanced Alloys



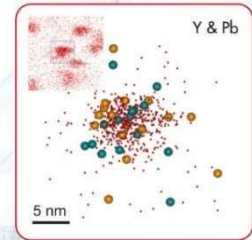
Thin Films



III/V LEDs



Biominerals



Geochemistry

Atom Probe Tomography (APT) is the highest spatial resolution analytical characterization technique with high efficiency single atom detection for quantitative atomic scale 3D elemental mapping of chemical heterogeneities (e.g. segregation, diffusion, precipitation and interfaces).

PROGRAM

- Atom Probe Tomography (APT): Operational Theory
- Introduction to APT Data Reduction
- Introduction to APT Sample Preparation
- APT Applications
 - Metals: Integration with Advanced Modeling
 - III/V: LED Devices
 - Semiconductor Devices: Planar and finFET
 - Geological Materials: Geochronology
- Correlative synergy
 - t-EBSD
 - TEM
- Atom Probe Tomography Instrumentation

SPEAKER



Dan Lawrence

Representing Atom Probe Tomography Instrumentation for CAMECA Instruments, Inc.

Dan has nearly 20 years of materials analysis experience, first as a staff member at the University of Wisconsin in Madison-WI then as an engineer at IBM microelectronics foundry in Burlington, VT. Since 2005, Dan has worked with Atom Probe Tomography instrumentation from within the applications group and most recently as a technical sales specialist at CAMECA.



REGISTRATION

Attendance is free of charge but space is limited! To register, please send an email with full contact details and a summary of your research interests before April 15th 2017 to: ybisrat@tamu.edu and keith.baxter@ametec.com

SPONSORING ORGANIZATIONS